

Sheet <u>1</u> of <u>1</u>		FORM PTO 1449 (modified)		ATTY DOCKET NO. YMOR:186		SERIAL NO. New Application		U.S. PATENT 09/697305 10/27/00	
U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE				APPLICANT Takaki YOSHIDA et al.*					
LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)				FILING DATE October 27, 2000				GROUP	

  

U.S. PATENT DOCUMENTS						
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	5,825,191	10/20/98	Niijima et al.	324	751	
	5,663,967	9/2/97	Lindberg et al.	371	26	
	5,640,403	6/17/97	Ishiyama et al.	371	26	
	4,769,817	9/6/88	Krohn et al.	371	23	
	6,044,208	3/28/00	Papadopoulou et al.	395	500	
	5,581,475	12/3/96	Majors	364	491	
	5,325,309	6/28/94	Halaviati et al.	364	488	

  

FOREIGN PATENT DOCUMENTS							
DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION NO YES		

  

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)	
	Defect-Based Test: A Key Enabler for Successful Migration to Structural Test, Intel Technology Journal Q1 '99, pp. 1-14.

  

EXAMINER:	DATE CONSIDERED: 5/19/2003
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\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.